



# 제25회 한국반도체학술대회

The 25<sup>th</sup> Korean Conference on Semiconductors

2018년 2월 5일(월)-7일(수), 강원도 하이원리조트 컨벤션 호텔

2018년 2월 7일(수), 16:15-17:30

Room G (봉래III+III, 6층)

## G. Device & Process Modeling, Simulation and Reliability 분과 [WG4-G] Memory and TFT - Modeling and Characterization

<b>WG4-G-1</b> 16:15-16:30	<b>TCAD Modeling of Endurance and Retention in NAND Flash Device</b> Dongyeon Oh, Bonghoon Lee, Eunmee Kwon, Sangyong Kim, Sungkye Park, Seong-Dong Kim, Seokkiu Lee, and Sungjoo Hong <i>Research and Development Division, SK Hynix Incorporated</i>
<b>WG4-G-2</b> 16:30-16:45	<b>유한요소법을 이용한 저항 메모리의 정전기적 거동에 대한 시뮬레이션</b> Kyung Hwan Min and Yong Woo Kwon <i>Department of Material science and Engineering., Hongik University</i>
<b>WG4-G-3</b> 16:45-17:00	<b>Study on Negative Bias Stress-Induced Instability in Zinc Oxynitride Thin-Film Transistors Using Systematic Decomposition</b> Hye Ri Yu, Jun Tae Jang, Geumho Ahn, Sung-Jin Choi, Dong Myong Kim, and Dae Hwan Kim <i>School of Electrical Engineering, Kookmin University</i>
<b>WG4-G-4</b> 17:00-17:15	<b>Extraction Method of Temperature-Independent Subgap Density-of-States of a-IGZO TFTs by Using Fermi-Dirac Distribution</b> Sungju Choi, Jae-Young Kim, Jaewon Kim, Jihyun Rhee, Hye Ri Yu, Hara Kang, Sung-Jin Choi, Dong Myong Kim, and Dae Hwan Kim <i>School of Electrical Engineering, Kookmin University</i>
<b>WG4-G-5</b> 17:15-17:30	<b>High-Temperature Characteristic of Low-Temperature Polycrystalline SiliconThin-Film Transistors (LTPS-TFTs) on Glass and Plastic Substrates</b> Soo Hyun Kim, Dong Hyun Kim, Kwan Hyun Cho, Dong Geun Park, and Jae Woo Lee <i>ICT Convergence Technology for Health &amp; Safety and Department of Electronics and Information Engineering, Korea University</i>